

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/815,976	FUKUI ET AL.	
Examiner		Art Unit		Page 1 of 1
Thanh-Truc Trinh		1753		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,885,368 A	03-1999	Lupo et al.	136/263
*	B	US-2002/0040728 A1	04-2002	Yoshikawa, Masaru	136/263
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004025748 A1	03-2004	World Intellect	ANDRIESSEN et al.	H01L 51/20
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Website Solaronix <a href="http://www.solaronix.ch/ruthenium/pdf/ruthenium620-1H3TBA_data_sheet.htm">http://www.solaronix.ch/ruthenium/pdf/ruthenium620-1H3TBA_data_sheet.htm</a> from 01/02/2000, 3 pages.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.